

Real Time Excursion Control for Nanomanufacturing Effectiveness
Erez Golan, Technology Project Manager, Applied Materials, Inc. and the College of
Nanoscale Science and Engineering - NanoEconomic Program. Albany NanoTech,
NY and Robert Teagle and Jennifer Braggin, IBM.

Abstract

A reliable real time On The Fly Automatic Defect Classification permits successful Automated Process/Tool Characterization (AP/TC) and rapid data reduction in the fab. This new approach moves the excursion control into a new era, which shows important fab productivity gains and significant cost savings. The paper presents a new method which significantly improved nanomanufacturing effectiveness at IBM Fab 323 EFK.